

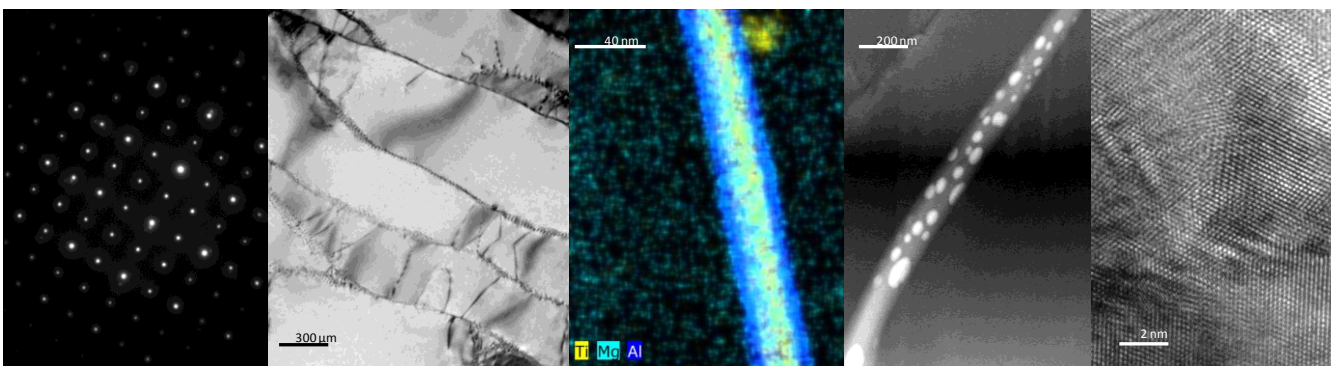


FEI TALOS FEG TEM

The FEI Talos Field Emission Gun (FEG) Transmission Electron Microscope (TEM) is built on an advanced operating platform for atomic lattice resolution imaging and nanoscale microanalysis. The TEM is equipped with highly sensitive Super-X EDS detectors for elemental analysis. This instrument is capable of 3D tomography investigations in all modes of operation (TEM, STEM and EDS).

Key Capabilities

- Atomic lattice resolution imaging, in both bright field and dark field, in TEM and Scanning Transmission Electron Microscope (STEM) modes
- Selected Area Electron Diffraction (SAED) and Convergent Beam Electron Diffraction (CBED)
- Energy Dispersive X-ray Spectroscopy (EDS) analysis, including elemental mapping
- Three dimensional imaging and EDS tomography
- Recording of real time dynamic experiments



An SAED pattern from a growing crystal in liquid metal

A diffraction contrast image of a nanostructured aluminium sample

An elemental map of a nanocomposite core-shell structure

A feldspar vein in volcanic cristobalite

An atomic lattice image of a nanostructured nickel sample

For more information

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